

Resource Summary Report

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Oxford: Ultim Extreme Electron Microscopy

RRID:SCR_020388

Type: Tool

Proper Citation

Oxford: Ultim Extreme Electron Microscopy (RRID:SCR_020388)

Resource Information

URL: <https://nano.oxinst.com/ultim-extreme>

Proper Citation: Oxford: Ultim Extreme Electron Microscopy (RRID:SCR_020388)

Description: Ultra high resolution FEG SEM application and delivers solutions beyond micro and nano analysis. It uses radical geometry for both imaging and EDS performance in ultra high resolution FEG SEMs while working at low kV and short working distance, with EDS resolution that approaches that of SEM.

Resource Type: instrument resource

Keywords: Oxford, Electron Microscopy, Instrument, Resource equipment, Equipment, USEDit,

Availability: Commercially available

Resource Name: Oxford: Ultim Extreme Electron Microscopy

Resource ID: SCR_020388

Alternate IDs: Model_Number_Ultim_Extreme

Record Creation Time: 20220129T080350+0000

Record Last Update: 20260801T190646+0000

Ratings and Alerts

No rating or validation information has been found for Oxford: Ultim Extreme Electron Microscopy.

No alerts have been found for Oxford: Ultim Extreme Electron Microscopy.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.